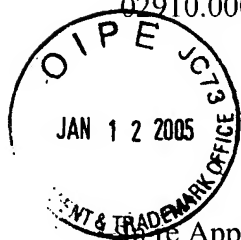


182

02910.000110.

PATENT APPLICATION



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Re Application of:

KAZUNARI OYAMA ET AL.

Application No.: 10/764,538

Filed: January 27, 2004

For: DRIVING METHOD FOR ELECTRON-
EMITTING DEVICE, DRIVING
METHOD FOR ELECTRON SOURCE,
MANUFACTURING METHOD FOR
ELECTRON SOURCE, AND IMAGE
DISPLAY APPARATUS

)
: Examiner: U.O. Anyaso
)
: Group Art Unit: 2675
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)
: January 11, 2005

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56 and in accordance with the practice under 37 C.F.R. §§ 1.97 and 1.98, the Examiner's attention is directed to the documents listed on the enclosed Form PTO-1449. Copies of the listed non-U.S. Patent documents are also enclosed.

For the concise explanation of relevance of non-English document JP 2000-95509, the Examiner is respectfully referred to the English abstract attached thereto, as

well as English-language counterpart U.S. Patent 6,455,021 B1.

Also, various non-English references listed on Form PTO-1449 are referred to in the specification, at least at pages 1-2, and the Examiner is referred to the relevant text on those pages for a concise statement of those respective non-English documents.

For the concise statement of relevance of Japanese document 2003-536215, the examiner is respectfully referred to the English Abstract attached thereto. Also, U.S. Patent 6,645,028, and International Publication No. WO 01/95360 belong to the same family as Japanese document 2003-536215. It also is noted that U.S. Patents 5,973,446, 5,588,893 and European Patent Publication No. 0 809 854 belong to the same family.

The Examiner's attention is also directed to the following U.S. Application:

<u>APPLICATION NO.</u>	<u>FILING DATE</u>	<u>GROUP ART UNIT</u>
09/506,289	02/18/00	2818

It is respectfully requested that the above information be considered by the Examiner and that a copy of the enclosed Form PTO-1449 be returned indicating that such information has been considered.

A check for \$180.00 is enclosed. Please change any fee deficiency and credit any overpayment to Deposit Account 06-1205.

Applicants' undersigned attorney may be reached in our New York office by telephone at (212) 218-2100. All correspondence should continue to be directed to our address given below.

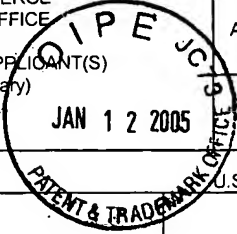
Respectfully submitted,



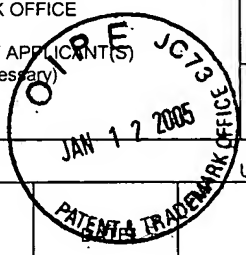
Frank A. DeLucia
Attorney for Applicants
Registration No. 42,476

FITZPATRICK, CELLA, HARPER & SCINTO
30 Rockefeller Plaza
New York, New York 10112-3800
Facsimile: (212) 218-2200

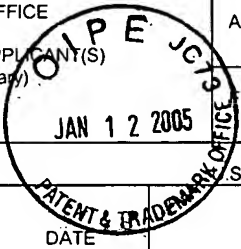
NY_MAIN # 412105v1

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			ATTY DOCKET NO. 02910.000110.		APPLICATION NO. 10/764,538	
			APPLICANT Kazunari Oyama et al.			
			FILING DATE January 27, 2004		GROUP N.Y.A.	
U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	2003/0048057 A1	03/13/03	Oyama et al.	313	311	
	2002/0009637 A1	01/24/02	Murakami et al.	429	213	
	5,847,495	12/08/98	Yamanobe et al.	313	310	
	2002/0132041 A1	09/19/02	Yamanobe et al.	427	77	
	6,246,168 B1	06/12/01	Kishi et al.	313	495	
	6,179,678 B1	01/30/01	Kishi et al.	445	24	
	6,147,449	11/14/00	Iwasaki et al.	313	495	
	6,171,162 B1	01/09/01	Iwasaki et al.	445	6	
	5,588,893	12/31/96	Kaftanov et al.	445	6	
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
	2000-95509	04/04/00	Japan	C01B	31/02	Abst. & Counterpart U.S. Patent 6,455,021
	1 291 889 A2	03/12/03	EPO	H01J	1/304	English
	0 913 508 A2	05/06/99	EPO	D01F	9/127	English
	1 187 161 A2	03/13/02	EPO	H01J	3/02	English
	1 245 704 A2	10/02/02	EPO	D01F	9/127	English
	WO 01/95360	12/13/01	PCT			English
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)						
	C.A. Spindt et al., <i>Physical Properties of Thin-Film Field Emission Cathodes with Molybdenum Cones</i>, Journal of Applied Physics, Vol. 47, No. 12, pp. 5248-5263 (1976)					
	S. Iijima, <i>Helical Microtubules of Graphitic Carbon</i>, Nature, Vol. 354, pp. 56-58 (1991)					
EXAMINER			DATE CONSIDERED			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			ATTY DOCKET NO. 02910.000110.		APPLICATION NO. 10/764,538	
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			FILING DATE January 27, 2004		GROUP N.Y.A.	
U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5,986,389	11/16/99	Tsukamoto	313	310	
	6,231,413 B1	05/15/01	Tsukamoto	445	24	
	6,184,610 B1	02/06/01	Shibata et al.	313	309	
	6,472,814 B1	10/29/02	Yamanobe et al.	313	495	
	6,288,494 B1	09/11/01	Tsukamoto et al.	315	169.1	
	2002/0057045 A1	05/16/02	Tsukamoto	313	309	
	2002/0074947 A1	06/20/02	Tsukamoto	315	169.3	
	2002/0060516 A1	05/23/02	Kawate et al.	313	495	
	2002/0031972 A1	03/14/02	Kitamura et al.	445	3	
	2003/0006684 A1	01/09/03	Kawate et al.	313	311	
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
	1 291 891 A2	03/12/03	EPO	H01J	3/02	English
	1 122 344 A2	08/08/01	EPO	D01F	9/127	English
	0 809 854	11/08/00	EPO			English
	2003-536215	12/02/03	Japan			Abstract
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)						
	Nikkei Mechanical, No. 567, pp.36-57 (2001)					
	V. Semet et al., <i>Field Electron Emission from Individual Carbon Nanotubes of a Vertically Aligned Array</i> , Applied Physics Letters, Vol. 81, No. 2, pp. 343-345 (2002)					
	P. Collins et al., <i>Unique Characteristics of Cold Cathode Carbon-Nanotube-Matrix Field Emitters</i> , Physical Review B, Vol.55, No. 15, pp. 9391-9399 (1997)					
EXAMINER			DATE CONSIDERED			

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U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	2003/0057860 A1	03/27/03	Tsukamoto	315	169.3	
	2003/0048055 A1	03/13/03	Ishikura et al.	313	311	
	2003/0162464 A1	08/28/03	Kyogaku et al.	445	24	
	4,904,895	02/27/90	Tsukamoto et al.	313	336	
	6,515,640 B2	02/04/03	Tsukamoto et al.	345	75.2	
	6,626,719 B2	09/30/03	Ono et al.	445	24	
	2003/0048056 A1	03/13/03	Kitamura et al.	313	311	
	2003/0124944 A1	07/03/03	Kyogaku et al.	445	6	
	2003/0048057 A1	03/13/03	Oyama et al.	313	311	
	2002/0047513 A1	04/25/02	Nomura	313	495	
	6,628,053 B1	09/30/03	Den et al.	313	310	
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	5,973,446	10/26/99	Kaftanov et al.	313	309	
	5,872,422	02/16/99	Xu et al.	313	311	
	5,773,921	06/30/98	Keesmann et al.	313	309	
	6,455,021 B1	09/24/02	Saito	423	447.3	
	5,973,444	10/26/99	Xu et al.	313	309	
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)						
	X. Xu et al., A Method for Fabricating Large-Area, Patterned, Carbon Nanotube Field Emitters" Applied Physics Letters, Vol. 74, No. 17, pp. 2549-2551 (1999)					
	Y. C. Choi et al., Controlling the Diameter, Growth Rate, and Density of Vertically Aligned Carbon Nanotubes Synthesized by Microwave Plasma-Enhanced Chemical Vapor Deposition", Applied Physics Letters, Vol. 76, No. 17, pp.2367-2369 (2000)					
EXAMINER				DATE CONSIDERED		

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